		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1372		SERIAL NO. 09/927,230			
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		FILING DATE August 9, 2001						GROUP 1762	
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	AA	6270572	08/2001	Kim et al	117	93			
	AB	6083832	07/2000	Sugai	438	672			
	AC	4369105	01/1983	Caldwell et al	204	290 F			
	AD	4831003	05/1989	Lang et al	502	182			
	AE	6287965	09/2001	Kang et al	438	648			
	AF	5480818	01/1996	Matsumoto et al	437	40			
	AG	6203613	03/2001	Gates et al	117	104			
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FOREIGN PATENT DOCUMENTS									
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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT		Trang Thi Dean	
				FILING DATE August 9, 2001		GROUP 1761	
U.S. PATENT DOCUMENTS							
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2 Sheet 1 of 2

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APPLICANT Trung Tri Doan

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*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
AA	5,270,247	12/1993	Sakuma et al.			
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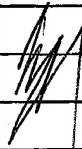
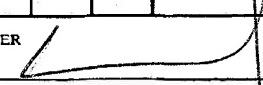
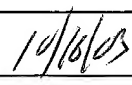
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

AM	Noah Precision, Inc., Internet website: <a href="http://www.noahprecision.com/tcc.htm">http://www.noahprecision.com/tcc.htm</a> ; "Thermoelectric Temperature Control" 1998, pps. 1-2.
AN	Noah Precision, Inc., Internet website: <a href="http://www.noahprecision.com/cvd.htm">http://www.noahprecision.com/cvd.htm</a> ; "CVD" 1998, pps. 1-2.
AO	Kiyoko et al., Patent Abstract Application No. 04-024917 (JP 9224917, 09/1993), "Semiconductor Substrate and Its Manufacture."
AP	Ritala, et al., "Atomic Layer Epitaxy - A Valuable Tool for Nanotechnology?" Nanotechnology, Vol. 10, No. 1, pps. 19-24, March 1999.
AQ	George, et al., "Surface Chemistry for Atomic Layer Growth", Journal of Physical Chemistry, Vol. 100, No. 31, pps. 13121-13131, August 1, 1996.
AR	Suntola, "Atomic Layer Epitaxy", Handbook of Crystal Growth, Vol. 3, Chapter 14, pps. 602-663, 1994.
AS	Vernon, S.M., "Low-cost, high-efficiency solar cells utilizing GaAs-on-Si technology." Dialog Abstract of Report No. NREL/TP-451-5353; 04/1993.

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	AA	09/643,004	Mercaldi			08/21/2000	
	AB	09/619,449	Derderian			07/19/2000	
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M122-1372SERIAL NO.  
09/927,230LIST OF ART CITED BY APPLICANT  
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APPLICANT Trung Tri Doan

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August 9, 2001GROUP  
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AB	5,281,274	1/1994	Yoder				
AC	5,388,555	11/1994	Kelly				
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AE	5,747,113	5/1998	Tsai				
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AG	5,116,840	5/1992	Mikami et al				
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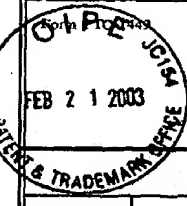

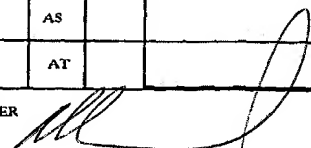

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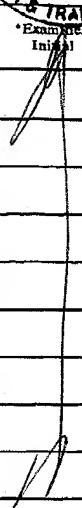
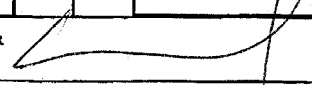
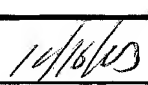
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		FILING DATE August 9, 2001		GROUP 1762				
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	AA	4,913,090	04/1990	Harada et al				
	AB	6,307,184	10/2001	Womack et al				
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	AD	6,203,618	03/2001	McMillan				
	AE	5,462,603	10/1995	Murakami				
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	AI	6,139,695	10/2000	Washburn et al				
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	AK	6,335,561	01/2002	Imoto				
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	AP		Aarik, et al, "Control of Thin Film Structure by Reactant Pressure in Atomic Layer Deposition of $\text{TiO}_2$ ", Journal of Crystal Growth, 169 (1996) pgs. 496-502					
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	AA	6,479,902	11/2002	Lopatin et al			
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	AD	6,235,871	05/2001	Doan			
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	AF	5,366,953	11/1994	Char et al			
	AG	5,273,930	12/1993	Steele et al			
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	AI	2002/0125516	09/2002	Marsh et al			
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[Signature]	AA	6,174,377	01-2001	Dosring et al			
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[Signature]	AM	Suntola, "Surface Chemistry of Materials Deposition at Atomic Layer Level", Applied Surface Science, vol. 100/101, March 1996, pp. 391-398.
[Signature]	AN	Aarik et al, "Effect of Growth Conditions on Formation of TiO <sub>2</sub> -II Thin Films in Atomic Layer Deposition Process", Journal of Crystal Growth, Vol. 181, August 1997, pp. 259-264.
	AO	Skarp, "ALE-Reactor for Large Area Depositions", Applied Surface Science, vol. 112, March 1997, pp. 251-254.
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EXAMINER [Signature]	DATE CONSIDERED 10/08/02
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